



## 基底和膜层-基底系统的赝布儒斯特角计算

刘华松<sup>1</sup>, 姜玉刚<sup>1,2</sup>, 王利栓<sup>1</sup>, 姜承慧<sup>1</sup>, 季一勤<sup>1,3</sup>

1. 天津航技术物理研究所 天津市薄膜光学重点实验室, 天津 300192;
2. 同济大学 物理系 先进微结构材料教育部重点实验室, 上海 200092;
3. 哈尔滨工业大学 光电子技术研究所 可调谐激光技术国家级重点实验室, 哈尔滨 150080

## Calculation of Pseudo-brewster Angle for Substrate and Thin Film-substrate System

LIU Hua-song<sup>1</sup>, JIANG Yu-gang<sup>1,2</sup>, WANG Li-shuan<sup>1</sup>, JIANG Cheng-hui<sup>1</sup>, JI Yi-qin<sup>1,3</sup>

1. Tianjin Key Laboratory of Optical Thin Film, Tianjin Jinhang Institute of Technical Physics, Tianjin 300192, China;
2. Key Laboratory of Advanced Micro-Structure Materials(Ministry of Education), Department of Physics, Tongji University, Shanghai 200092, China;
3. National Key Laboratory of Science and Technology on Tunable Laser, Institute of Optical-electronics, Harbin Institute of Technology, Harbin 150080, China

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